

<b>Notice of References Cited</b>	Application/Control No. 09/754,073	Applicant(s)/Patent Under Reexamination MEIER ET AL.	
	Examiner Crystal J. Barnes	Art Unit 2121	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,987,508	11-1999	Agraharam et al.	709/217
	B	US-6,023,700	02-2000	Owens et al.	707/10
	C	US-6,085,231	07-2000	Agraharam et al.	709/206
	D	US-6,014,711	01-2000	Brown, Anne R.	709/245
	E	US-6,292,799	09-2001	Peek et al.	707/10
	F	US-6,333,973	12-2001	Smith et al.	379/88.12
	G	US-6,356,937	03-2002	Montville et al.	709/206
	H	US-6,363,140	03-2002	Pinard, Debbie	379/88.22
	I	US-6,400,810	06-2002	Skladman et al.	379/93.24
	J	US-6,498,797	12-2002	Anerousis et al.	370/522
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	US Pub. No. 2002/0176117 A1 to RANDALLI et al.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.